


INFORMATION DISCLOSURE CITATION
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US Div'l of 10/465,075

Naor WAINER et al.

FILING

Herewith

GROUP

To be assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	1	4,210,805	1 Jul '80	KOBAYASHI, T. et al.			
	2	4,755,676	5 Jul '88	GAALEMA, S. et al.			
	3	5,677,539	14 Oct '97	APOTOVSKY, B. et al.			
	4	5,777,338	7 Jul '98	HE, Z.			
	5	5,821,539	13 Oct '98	MATZ, R. et al.			
	6	6,034,373	7 Mar '00	SHAHAR, A. et al.			
	7	6,169,287	2 Jan '01	WARBURTON, W. K.			
	8	6,583,420	June 2003	NELSON, et al.			
	9	6,333,504	Dece 2001	LINGREN, et al.			
	10	2002/0079456	June 2002	LINGREN, et al.			
	11	5,500,534	March 1996	ROBINSON, et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES
	12	CH 471 392	15 Apr '69	SWITZERLAND			
	13	DE 196 16 545	30 Oct '97	GERMANY			
	14	EP 0 291 351	17 Nov '88	EUROPE			
	15	EP 0 527 373	17 Feb '93	EUROPE			
	16	FR 2 705 791	2 Dec '94	FRANCE			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	17	HE, Z. et al.; "Coplanar Grid Patterns and Their Effect on Energy Resolution of CdZnTe Detectors;" IEEE Nuclear Science Symposium and Medical Imaging Conference; Albuquerque, Mexico; 9-15 November 1997
	18	NAOAKI, I.; JP 02-163691 A; 22 June 1990 & Patent Abstracts of Japan; Vol. 014; No. 422 (P-1104); 12 September 1990

EXAMINER

DATE CONSIDERED

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